



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei YAMAZAKI et al. Art Unit : 2871
Serial No. : 09/809,646 Examiner : Unknown
Filed : March 16, 2001
Title : SEMICONDUCTOR DISPLAY DEVICE AND MANUFACTURING METHOD
THEREOF

Commissioner for Patents
Washington, D.C. 20231

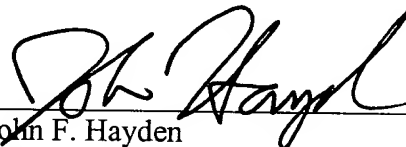
INFORMATION DISCLOSURE STATEMENT

Applicants submit the references listed on the attached form PTO-1449, copies of which are enclosed. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed before issuance of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: June 12, 2002



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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-021001	Application No. 09/809,646
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.	
		Filing Date March 16, 2001	Group Art Unit 2871

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,394,182	07/19/1983	Maddox, III			10/14/1981
	AB	5,272,100	12/21/1993	Satoh et al.			12/21/1993
	AC	5,750,430	05/12/1998	Son			08/23/1996
	AD	5,828,103	10/27/1998	Hsu			12/26/1995
	AE	5,986,305	11/16/1999	Wu			03/30/1998
	AF	6,031,290	02/29/2000	Miyazaki et al.			03/13/1998
	AG	6,369,410	04/09/2000	Yamazaki et al.			12/15/1998
	AH						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AI	6-148685	05/27/1994	Japan			Abs	
	AJ	7-235680	09/05/1995	Japan			Abs	
	AK	8-274336	10/18/1996	Japan			Abs	
	AL	10-233511	09/02/1998	Japan			Abs	
	AM	11-261075	09/24/1999	Japan			Abs	
	AN	2001-210832	08/03/2001	Japan			Abs	
	AO	EP 1 001 467 A2	05/17/2000	Europe				
	AP	EP 1 003 223 A2	05/24/2000	Europe				

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	